



# LST-2500HD

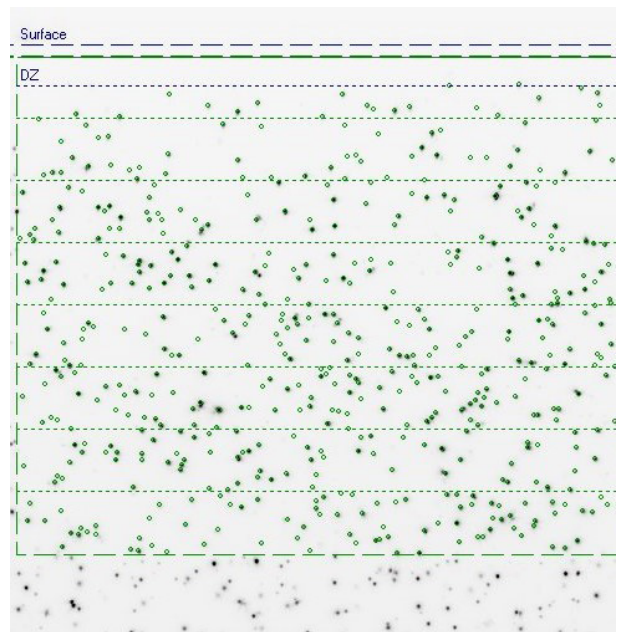
## LIGHT SCATTERING TOMOGRAPH MICRO- AND GROWN-IN DEFECT ANALYZER

The Light Scattering Tomograph (LST) is the industrial standard inspection system for Bulk Micro Defect (BMD) detection. The latest tool generation: LST-2500HD possesses superior performance in all important features that a light scanning tomograph can have. The acronym HD indicates these enhanced features like High Dynamic range, High Detectability, and High Detection speed.



## Facts

- Non-contact, whole wafer diameter scan
- Effective automated measurement and evaluating of BMD data
- Improved resolution for high density wafers
- Automatic evaluation during measurements
- Automatic defect finding and surface scattering exclusion algorithm
- Various reporting possibilities on defect statistics and DZ

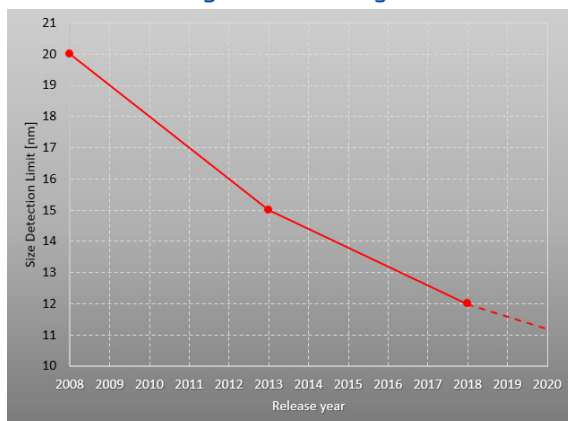


Bulk Micro Defects

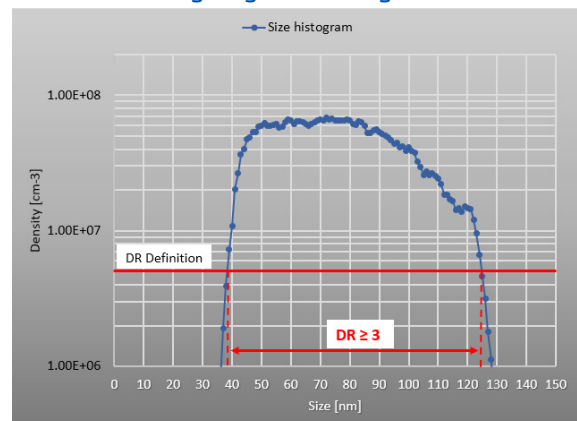
## Benefits

- High sensitivity, defect detection down to 12 nm in size
- High dynamic range ( $\geq 3$ ) to cover the widest size range available with one laser power setting
- Excellent reproducibility allows the measurement of the size of the same individual defect before and after thermal treatment
- Outstanding stability and excellent Tool-to-Tool matching
- Engineer-independent adjustment procedures
- Beam characterization: improved beam diameter measurement, beam shape and tilt measurement

High Detectability



High Dynamic Range



This material is for information purposes only. Equipment acceptance is based on contracted specifications.

